Se	arch	No	tes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/510,371	PETEREIT ET AL.	
Examiner	Art Unit	
Michael Bernshteyn	1713	

SEARCHED			
Class	Subclass	Date	Examiner
526	319	2/27/2006	МВ
526	317.1	2/27/2006	МВ
526	328	2/27/2006	МВ
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NO (INCLUDING SEARCH		)
	DATE	EXMR
EAST (USPAT, JPO, EPO,DERWENT, PREGRANT	2/27/2006	МВ
PALM, eDAN Inventors and Assignee search update	2/27/2006	МВ
NPL	2/27/2006	мв